

AMENDMENTS TO THE CLAIMS:

Complete Listing of Claims

Claim 1. (currently amended) A method of measuring jitter in a device under test comprising the steps of:

- providing a coherent sample signal to the device under test;
- unwrapping the data from the device;
- performing FFT of the unwrapped data;
- removing the DC harmonic and the fundamental frequency from the FFT of the unwrapped data;
- performing an inverse FFT of the FFT of the unwrapped data with the DC harmonic and fundamental removed to get a code error;
- adjusting the code error to a predetermined phase;
- determining the variance of the code error at a the low slew rate;
- determining the variance of the code error at a the high slew rate; and
- calculating the jitter on each angle from the variance of the code error determined at the high slew rate variance by each angle and the variance of the code error determined at the low slew rate variance.

Claim 2. (currently amended) The method of claim 1 wherein said method includes the step of removing sparkle codes before adjusting the ~~phase~~ code error.

Claim 3. (original) The method of claim 2 including the step of averaging the jitter for all angles that the jitter is calculated.

Claim 4. (original) The method of claim 1 including the step of averaging the jitter for all angles that the jitter is calculated.